







TPS7B4256-Q1 SBVS397A - SEPTEMBER 2023 - REVISED NOVEMBER 2023

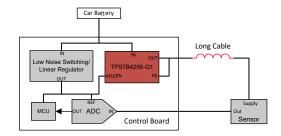
TPS7B4256-Q1 Automotive, 70-mA, 40-V, Voltage-Tracking LDO With 6-mV Tracking **Tolerance**

1 Features

- AEC-Q100 qualified for automotive applications:
 - Temperature grade 1: –40°C to +125°C, T_A
 - Junction temperature: –40°C to +150°C, T_J
- Wide input voltage range:
 - Absolute maximum range: –40 V to +45 V
 - Operating range: 3 V to 40 V
- · Output voltage:
 - Wide operating range: 2 V to 40 V
 - Output voltage flexibility: V_{OUT} can be scaled to values that are higher or lower than the reference using external resistors in a voltage divider configuration
- Maximum output current: 70 mA
- Very tight output-tracking tolerance: 6 mV (max)
- Low dropout voltage: 225 mV (max) at 70 mA
- Combined enable and reference functionalities
- Low quiescent current at light load: 60 µA
- Stable over a wide range of ceramic output capacitor values:
 - C_{OUT} range: 1 μ F to 100 μ F
 - ESR range: 1 mΩ to 2 Ω
- Integrated protection features:
 - Reverse current protection
 - Reverse polarity protection
 - Overtemperature protection
 - Protection against output short circuit to ground and supply
- Available in the following low thermal resistance 8-pin packages:
 - HSOIC (DDA), $R_{\theta JA} = 53.3$ °C/W
 - SOIC (D), $R_{0.1A} = 101^{\circ}$ C/W

2 Applications

- Powertrain pressure sensors
- Powertrain temperature sensors
- Powertrain exhaust sensors
- Powertrain fluid concentration sensors
- Body control modules (BCM)



Typical Application

3 Description

The TPS7B4256-Q1 is a monolithic, integrated, low-dropout (LDO) voltage tracker. The device is available in 8-pin SOIC and HSOIC packages. The TPS7B4256-Q1 is designed to provide power supply to off-board sensors in an automotive environment. Because the risk of failure in cables that deliver off-board power is high, the device comes with integrated protection features against fault conditions such as short to battery, reverse polarity, output short to ground (current limit), and overtemperature (thermal shutdown). The device incorporates a backto-back PMOS topology that eliminates the need for an external diode that is otherwise required to help protect against fault conditions that result in flow of reverse current. The device is designed to handle a 45-V (absolute maximum) input voltage and survive the automotive load dump transient conditions.

A reference voltage applied at the adjustable input pin (ADJ/EN) is tracked with a very tight 6 mV (max) tolerance at the FB pin across temperature. This tracking enables the TPS7B4256-Q1 to deliver a power-supply voltage with high precision for loads up to 70 mA. The reference voltage can be directly connected to the ADJ/EN pin or scaled down to lower values with the help of an external resistor divider at the ADJ/EN pin to a minimum of 2 V. The output voltage can be made equal to the voltage at the ADJ/EN pin (± the tracking tolerance) by tying the FB pin directly to the OUT pin or scaled to higher values with the help of a resistive voltage divider between the FB and the OUT pin.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE(2)
TPS7B4256-Q1	DDA (HSOIC, 8)	4.9 mm × 6 mm
1F31D4230-Q1	D (SOIC, 8)	4.5 111111 ~ 0 111111

- For more information, see the Mechanical, Packaging, and Orderable Information.
- The package size (length × width) is a nominal value and includes pins, where applicable.



The TPS7B4256-Q1 provides an effective buffer to the reference voltage of an ADC and securely transmits this voltage (or a scaled version thereof) over a long cable to power off-board sensors. If the sensor is ratiometric and the output is sampled by the ADC, the described features of the TPS7B4256-Q1 help significantly improve the reliability and accuracy of the sensor measurements.

By setting the ADJ/EN input pin low, the TPS7B4256-Q1 switches to standby mode and reduces the quiescent current consumption of the LDO to less than $3.5 \,\mu\text{A}$.



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4 Pin Configuration and Functions

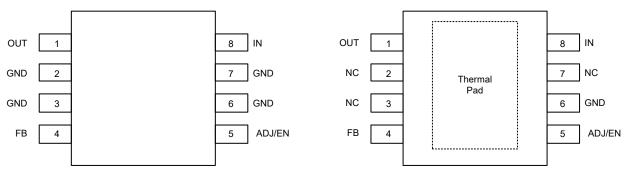


Figure 4-1. D Package, 8-Pin SOIC (Top View)

Figure 4-2. DDA Package, 8-Pin HSOIC (Top View)

Table 4-1. Pin Functions

	PIN		TYPE DESCRIPTION		
NAME	D	DDA	ITPE	DESCRIPTION	
ADJ/EN	5	5	I	Adjustable/enable input pin. Connect the external reference voltage to this pin. This pin connects to the inverting input of the error amplifier internally. A low signal below V_{IL} disables the device, and a high signal above V_{IH} enables the device. Connect the voltage reference directly, or with a voltage divider to attain output voltages lower than the reference; see the <i>Tracker Output Voltage</i> (V_{OUT}) section for more details. To compensate for line influences, place a 0.1- μ F capacitor close to this pin.	
FB	4	4	I	Feedback pin. This pin is connected to the noninverting input of the error amplifier internally and can be used to control the output voltage. For output voltages equal to or less than the external reference voltage, connect this pin directly to the output pin. To attain output voltage values higher than the reference, use a voltage divider with external feedback resistors; see the <i>Tracker Output Voltage</i> (<i>V_{OUT}</i>) section for more details.	
GND	2, 3, 6, 7	6	G	GND pin. Connect this pin to a low impedance path to ground.	
IN	8	8	I	Input power-supply voltage pin. For best transient response and to minimize input impedance, use the recommended value or larger ceramic capacitor from IN to GND, as listed in the <i>Recommended Operating Conditions</i> table. Place the input capacitor as close to the input pin of the device as possible to compensate for line influences.	
NC	_	2, 3, 7	_	Not internally connected. For best thermal performance, connect these pins to GND.	
OUT	1	1	0	Regulated output voltage pin. A capacitor is required from OUT to GND for stability. For best transient response, use the nominal recommended value or larger ceramic capacitor from OUT to GND; see the <i>Recommended Operating Conditions</i> table. Place the output capacitor as close to output of the device as possible.	
Thermal Pad	_	Pad		Thermal pad. Connect the pad to GND for best possible thermal performance.	



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
V _{IN}	Unregulated input	-40	45	٧
V _{OUT}	Regulated output	-5	45	V
V _{FB}	Feedback	-5	45	V
V _{ADJ/EN}	Adjustable reference and enable input voltage	-40	45	V
TJ	Operating junction temperature	-40	150	°C
T _{stg}	Storage temperature	-65	150	°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may effect the device reliability, functionality, performance, and shorten the device lifetime.

5.2 ESD Ratings

				VALUE	UNIT
		Human-body model (HBM), per AEC Q100-00)2 ⁽¹⁾	±2500	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per AEC	All pins	±1000	V
		Q100-011	Corner pins	±1000	

⁽¹⁾ AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	TYP	MAX	UNIT
V _{IN}	Input voltage	3		40	V
V _{OUT}	Output voltage	2		40	V
V _{ADJ/EN}	Adjust pin voltage	2		40	V
V _{FB}	Feedback pin voltage	0		40	V
I _{OUT}	Output current	0		70	mA
C _{IN}	Input capacitor ⁽¹⁾		1		μF
C _{OUT}	Output capacitor ⁽²⁾	1		100	μF
ESR	Output capacitor ESR requirements	0.001		2	Ω
TJ	Operating junction temperature	-40		150	°C

⁽¹⁾ For robust EMI performance the minimum input capacitance recommended is 500 nF.

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⁽²⁾ Effective output capacitance of 500 nF minimum is required for stability.



5.4 Thermal Information

		TPS7	B4256-Q1	
	THERMAL METRIC ⁽¹⁾ (2)	D (SOIC)	DDA (HSOIC)	UNIT
		8 PINS	8 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	100.9	53.3	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	50.2	75.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	38.3	28.1	°C/W
ΨЈТ	Junction-to-top characterization parameter	8.4	10.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	37.9	28	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	-	13.3	°C/W

- (1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application note.
- (2) The thermal data is based on the JEDEC standard high-K board layout, JESD 51-7. This is a two-signal, two-plane, four-layer board with 2-oz. copper on the external layers. The copper pad is soldered to the thermal land pattern. Also, correct attachment procedure must be incorporated.

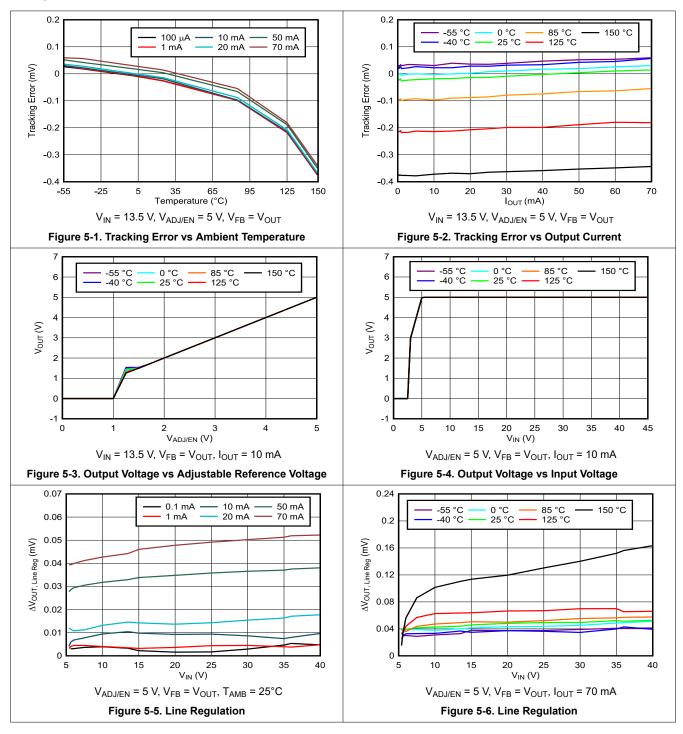
5.5 Electrical Characteristics

specified at T_J = -40°C to +150°C, V_{IN} = 13.5 V, V_{OUT} = V_{FB}, I_{OUT} = 100 μ A, C_{OUT} = 1 μ F, C_{IN} = 1 μ F and V_{ADJ/EN} = 5 V (unless otherwise noted); typical values are at T_J = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		V_{IN} = 5.4 V to 40 V, $V_{ADJ/EN}$ = 5 V, I_{OUT} = 100 μ A, T_{J} = 25°C		50	60	
IQ	Quiescent current	V_{IN} = 5.4 V to 40 V, $V_{\text{ADJ/EN}}$ = 5 V, I_{OUT} = 100 $\mu\text{A}, -40^{\circ}\text{C} < T_{\text{J}}$ $< 85^{\circ}\text{C}$		-	65	μΑ
		V_{IN} = 5.4 V to 40 V, $V_{ADJ/EN}$ = 5 V, I_{OUT} = 100 μA			70	
I _{GND}	Ground current	V _{IN} = 5.4 V to 40 V, V _{ADJ/EN} = 5 V, I _{OUT} = 70 mA			1	mA
I _{SHUTDOWN}	Shutdown supply current	V _{EN} = 0 V			3.5	μA
I _{ADJ/EN}	ADJ/EN pin current	I _{OUT} = 100 μA to 70 mA			0.9	μA
V _{UVLO(RISING)}	Rising input supply UVLO	V _{IN} rising, I _{OUT} = 5 mA	2.6	2.7	2.85	V
V _{UVLO(FALLING)}	Falling input supply UVLO	V _{IN} falling, I _{OUT} = 5 mA	2.3	2.4	2.5	V
V _{UVLO(HYST)}	V _{UVLO(IN)} hysteresis			300		mV
V _{IL}	Enable logic input low level				0.8	V
V _{IH}	Enable logic input high level		1.8			V
V _{OUT}	Regulated output	V _{IN} = V _{OUT} + 400 mV to 40 V, I _{OUT} = 100 μA to 70 mA	-6		6	mV
$\Delta V_{OUT(\Delta VIN)}$	Line regulation	V _{IN} = V _{OUT} + 400 mV to 40 V, I _{OUT} = 100 μA	-0.4		0.4	mV
$\Delta V_{OUT(\Delta IOUT)}$	Load regulation	$V_{IN} = V_{OUT} + 400 \text{ mV}, I_{OUT} = 100 \mu\text{A to 70 mA}$ (1)	-0.5		0.5	mV
V _{DO}	Dropout voltage	I _{OUT} = 70 mA, V _{ADJ/EN} ≥ 3.3 V, V _{IN} = V _{ADJ/EN}		130	225	mV
I _{CL}	Output current limit	V _{IN} = V _{OUT} + 1 V, V _{OUT} short to 90% x V _{ADJ/EN}	85	105	125	mA
PSRR	Power-supply ripple rejection	V _{RIPPLE} = 1 V _{PP} , frequency = 100 Hz, I _{OUT} ≥ 5 mA		80		dB
Vn	Output noise voltage	V_{OUT} = 3.3 V, I_{OUT} = 1 mA, a 5 μV_{RMS} reference is used for this measurement		150		μV_{RMS}
I _{REV}	Reverse current at V _{IN}	V _{IN} = 0 V, V _{OUT} = 32 V, V _{ADJ/EN} = 5 V	-0.6		0.6	μA
I _{REV-N1}	Reverse current at negative V _{IN}	V _{IN} = -20 V, V _{OUT} = 20 V, V _{ADJ/EN} = 5 V	-1.1		1.1	μA
I _{REV-N2}	Reverse current at negative V _{IN}	V _{IN} = -20 V, V _{OUT} = 0 V, V _{ADJ/EN} = 5 V	-0.6		0.6	μA
I _{FB}	Feedback pin current			0.1	0.25	μA
T _J	Junction temperature		-40		150	°C
T _{SD(SHUTDOWN)}	Junction shutdown temperature			175		°C
T _{SD(HYST)}	Hysteresis of thermal shutdown			15		°C

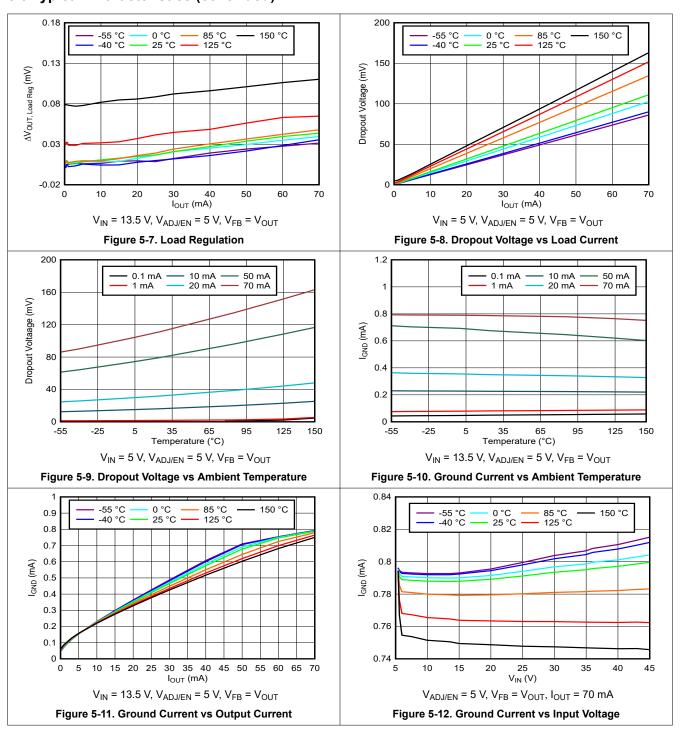
(1) Power dissipation is limited to 2 W for device production testing purposes. The power dissipation can be higher during normal operation. See the thermal dissipation section for more information on how much power the device can dissipate while maintaining a junction temperature below 150°C.

5.6 Typical Characteristics



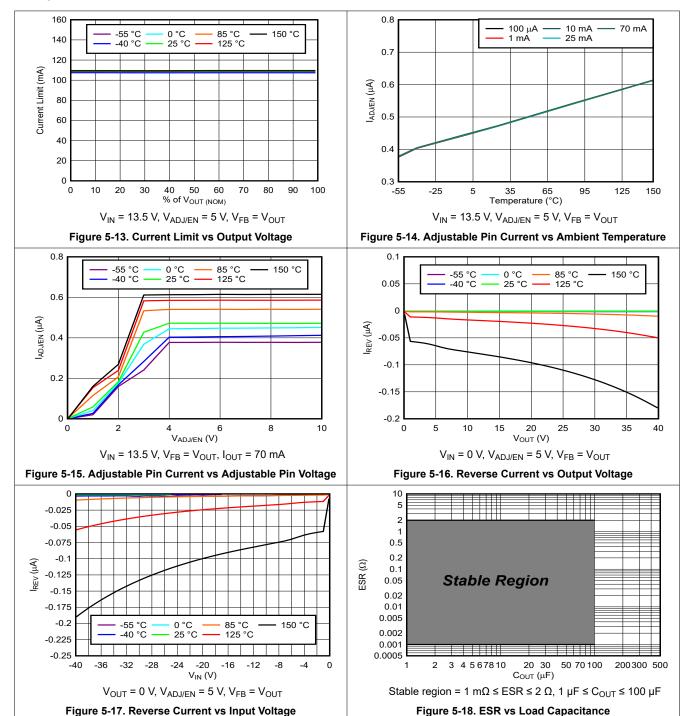


5.6 Typical Characteristics (continued)



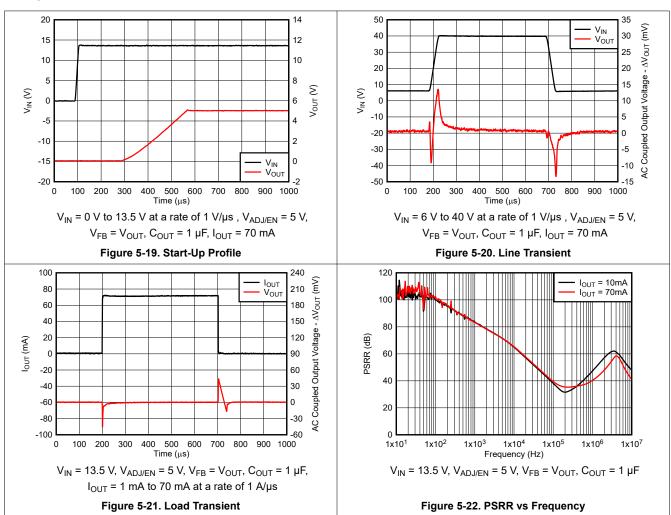


5.6 Typical Characteristics (continued)





5.6 Typical Characteristics (continued)



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6 Detailed Description

6.1 Overview

The TPS7B4256-Q1 is an integrated, low-dropout (LDO) voltage tracker with ultra-low tracking tolerance. Because of the high risk of cable shorts when powering off-board sensors, multiple features are built into the LDO to protect against fault conditions resulting in short to battery, short to GND, and reverse current protection.

In addition, this device also features thermal shutdown protection, brick-wall current limiting, undervoltage lockout (UVLO), and reverse polarity protection.

6.2 Functional Block Diagram

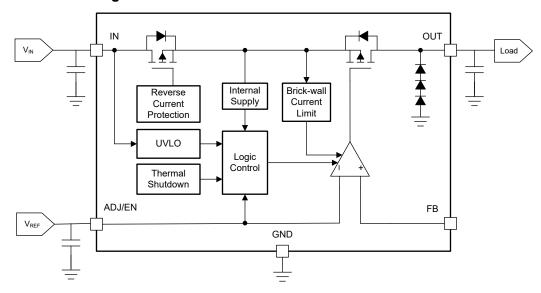


Figure 6-1. Functional Block Diagram

6.3 Feature Description

6.3.1 Tracker Output Voltage (VOUT)

Because this device is a tracking LDO, the output voltage is determined by the voltage provided to the ADJ/EN pin. The LDO remains disabled as long as $V_{ADJ/EN}$ is less than V_{IL} . When $V_{ADJ/EN}$ exceeds V_{IH} , the output voltage V_{OUT} begins to rise. The device has a soft-start feature incorporated, which allows the output voltage to rise linearly and limits the in-rush current at start-up. After start-up and upon attaining steady state, the feedback pin voltage V_{FB} remains within ± 6 mV from the voltage set on the ADJ/EN pin over all specified operating conditions.

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6.3.1.1 Output Voltage Equal to Reference Voltage

As shown in Figure 6-2, with the external reference voltage applied directly to the ADJ/EN pin and the FB pin connected to the OUT pin, the LDO output voltage is equal to the reference voltage, as given in Equation 1.

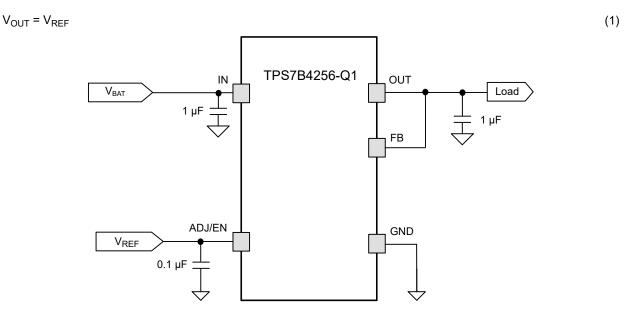


Figure 6-2. Tracker Output Voltage equal to Reference Voltage

6.3.1.2 Output Voltage Less Than the Reference Voltage

Connecting an external resistor divider at the ADJ/EN pin, as shown in Figure 6-3, can help generate an output voltage that is lower than the reference voltage. Both R_1 and R_2 must be less than 100 k Ω to minimize the error in voltage caused by the ADJ/EN pin leakage current, $I_{ADJ/EN}$. Equation 2 calculates V_{OUT} .

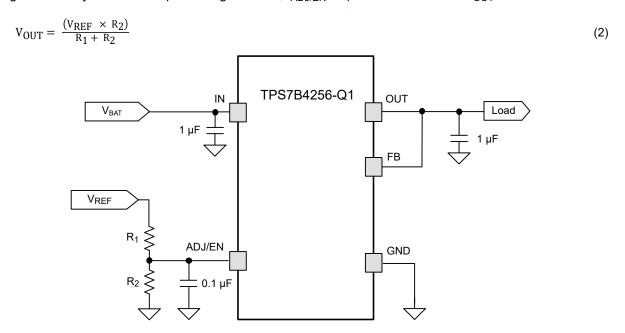


Figure 6-3. Tracker Output Voltage Lower Than the Reference Voltage

6.3.1.3 Output Voltage Larger Than the Reference Voltage

Connecting an external resistor divider between the OUT and FB pin, as shown in Figure 6-4, can help generate an output voltage that is higher than the reference voltage. Both R_1 and R_2 must be less than 100 k Ω to minimize the error in voltage caused by the FB pin leakage current, I_{FB} . Equation 3 calculates V_{OUT} .

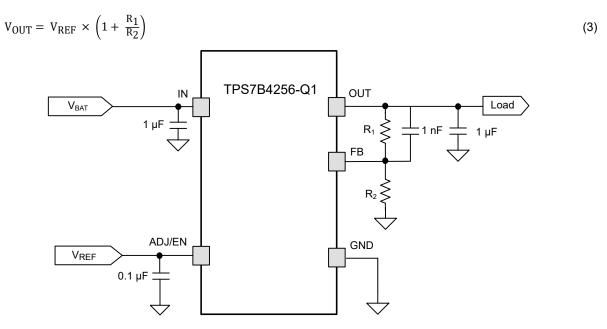


Figure 6-4. Tracker Output Voltage Higher Than the Reference Voltage

6.3.2 Reverse Current Protection

The TPS7B4256-Q1 incorporates a back-to-back PMOS topology that protects the device from damage against a fault condition, resulting in V_{OUT} being higher than V_{IN} and the subsequent flow of reverse current. No damage occurs to the device if this fault condition occurs, provided the *Absolute Maximum Ratings* are not violated. This integrated protection feature eliminates the need for an external diode. The reverse current comparator typically responds to a reverse voltage condition in 1 μ s, and along with the body diode of the blocking PMOS transistor, limits the reverse current to I_{REV} .

6.3.3 Undervoltage Lockout

The device has an internally fixed undervoltage lockout (UVLO) threshold. Undervoltage lockout activates when the input voltage V_{IN} drops below the undervoltage lockout level (see the $V_{UVLO(FALLING)}$ parameter in the *Electrical Characteristics* table). This activation makes sure that the regulator is not latched into an unknown state during a low input supply voltage. If the input voltage has a negative transient that drops below the UVLO threshold and recovers, the regulator shuts down and powers up in the standard power-up sequence when the input voltage recovers to the required level (see the $V_{UVLO(RISING)}$ parameter in the *Electrical Characteristics* table).

6.3.4 Thermal Protection

Thermal protection disables the output when the junction temperature rises to approximately 175°C, which allows the device to cool. When the junction temperature cools to approximately 160°C, the output circuitry enables. Although the device can enable at such high temperatures, the device parameters and performance are specified up to a junction temperature of 150°C. Based on power dissipation, thermal resistance, and ambient temperature, the thermal protection circuit can cycle off and on until the condition that causes excessive power dissipation is removed. This cycling limits the dissipation of the regulator, thus protecting the regulator from damage as a result of overheating.

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The internal protection circuitry of the TPS7B4256-Q1 is designed to protect against overload conditions. This circuitry is not intended to replace proper heat sinking. Continuously running the TPS7B4256-Q1 into thermal shutdown degrades device reliability.

6.3.5 Current Limit

The device has an internal current limit circuit to protect the device during overcurrent or shorting conditions. The current-limit circuit, as shown in Figure 6-5, is a brick-wall scheme. When the device is in current limit, the device sources I_{CL} and the output voltage is not regulated. In this scenario, the output voltage depends on the load impedance.

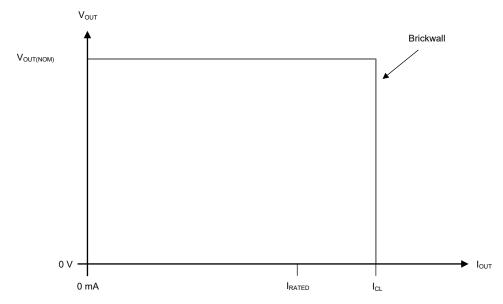


Figure 6-5. Current Limit: Brick-Wall Scheme

During a current-limit event, the potential for high power dissipation exists because of the elevated current level and the increased input-to-output differential voltage $(V_{\text{IN}} - V_{\text{OUT}})$. If the device heats enough, the device can enter thermal shutdown. If the current-limit condition is not removed when the device turns back on after cooling, the device can enter thermal shutdown again and continue this cycle until the current-limit condition is removed. The device survives this fault, but repeatedly operating in this mode degrades long-term reliability.

6.3.6 Output Short to Battery

When the output is shorted to the battery (see Figure 6-6), the TPS7B4256-Q1 survives and no damage occurs to the device. A short to the battery can also occur when the device is powered by an isolated supply (see Figure 6-7) at a lower voltage. In this case, the TPS7B4256-Q1 supply input voltage is set at 7 V when a short to battery (14 V typical) occurs on V_{OUT} , which typically runs at 5 V. The back-to-back PMOS topology helps limit the continuous reverse current flowing through V_{IN} to I_{REV} , as provided in the *Electrical Characteristics* table.

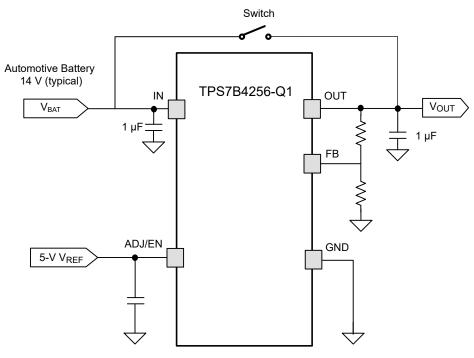


Figure 6-6. Output Voltage Short to Battery

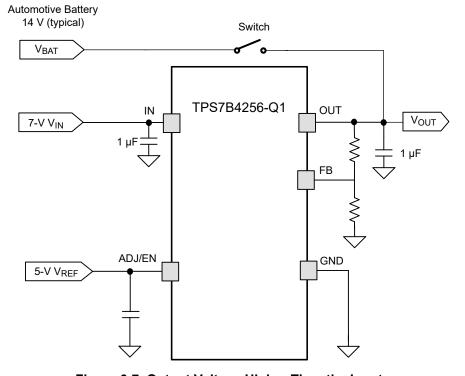


Figure 6-7. Output Voltage Higher Than the Input



6.3.7 Tracking Regulator With an Enable Circuit

By pulling the reference voltage below V_{IL} , the device disables and enters a sleep state where the device draws 3.5 μ A (max) from the power supply. In a typical application, the reference voltage is generally sourced from another LDO voltage rail. A scenario where the device must be disabled without a shutdown of the reference voltage can occur. The device can be configured as shown in Figure 6-8 in this case. The TPS7B84-Q1 is a 150-mA LDO with ultra-low quiescent current that provides the reference voltage to both the TPS7B4256-Q1 and the ADC. The operational status of the device is controlled by a microcontroller (MCU) input or output (I/O).

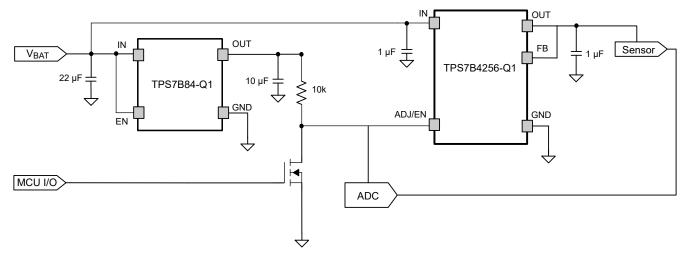


Figure 6-8. Tracking an LDO With an Enable Circuit

6.4 Device Functional Modes

Table 6-1 shows the conditions that lead to the different modes of operation. See the *Electrical Characteristics* table for parameter values.

Table 6-1. Device Functional Mode Comparison	Table 6-1.	Device	Functional	Mode	Comparison
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OPERATING MODE	PARAMETER ⁽¹⁾						
OPERATING WIDDE	V _{IN}	V _{ADJ/EN}	I _{OUT}	T _J			
Normal operation	$V_{IN} > V_{OUT(Nom)} + V_{DO}$ and $V_{IN} \ge V_{IN(min)}$	V _{ADJ/EN} > V _{IH}	I _{OUT} ≤ I _{OUT(max)}	$T_J < T_{SD(shutdown)}$			
Dropout operation	$V_{IN(min)} < V_{IN} < V_{OUT(nom)} + V_{DO}$	V _{ADJ/EN} > V _{IH}	I _{OUT} ≤ I _{OUT(max)}	T _J < T _{SD(shutdown)}			
Disabled (any true condition disables the device)	V _{IN} < V _{UVLO}	V _{ADJ/EN} < V _{IL}	Not applicable	$T_{J} > T_{SD(shutdown)}$			

⁽¹⁾ The device turns on when V_{IN} is greater than V_{UVLO(RISING)} and V_{ADJ/EN} is greater than the enable rising threshold V_{IH}.

6.4.1 Normal Operation

The device output voltage $V_{OUT(Nom)}$ tracks the reference voltage at the ADJ/EN pin when the following conditions are met:

- The input voltage is at least 3 V (V_{IN(min)}) and greater than the nominal output voltage plus the dropout voltage (V_{OUT(nom)} + V_{DO})
- The reference voltage at the ADJ/EN pin is greater than the enable rising threshold V_{IH} and stays stable at the appropriate V_{REF} value
- The output current is less than I_{OUT(max)} (I_{OUT} ≤ 70 mA)
- The device junction temperature is less than the thermal shutdown temperature (T_J < T_{SD})

6.4.2 Dropout Operation

If the input voltage is lower than the nominal output voltage plus the specified dropout voltage, but all other conditions are met for normal operation, the device operates in dropout mode. In this mode, the output voltage tracks the input voltage. During this mode, the transient performance of the device becomes significantly degraded because the pass transistor is in the ohmic or triode region, and acts as a switch. Line or load transients in dropout can result in large output-voltage deviations.

When the device is in a steady dropout state (defined as when the device is in dropout, $V_{IN} < V_{OUT(NOM)} + V_{DO}$, directly after being in a normal regulation state, but *not* during start up), the pass transistor is driven into the ohmic or triode region. When the input voltage returns to a value greater than or equal to the nominal output voltage plus the dropout voltage ($V_{OUT(NOM)} + V_{DO}$), the output voltage can overshoot for a short period of time while the device pulls the pass transistor back into the saturation region.

6.4.3 Operation With V_{IN} < 3 V

For input voltages below 3 V and above $V_{UVLO(FALLING)}$, the LDO continues to operate but certain internal circuits can possibly not have the proper headroom to operate within specification. When the input voltage drops below $V_{UVLO(FALLING)}$ the device shuts off.

6.4.4 Disable With ADJ/EN Control

The ADJ/EN pin operates as both the reference and the enable pin to the LDO. The output of the device can be shutdown by forcing $V_{ADJ/EN}$ less than V_{IL} . When disabled, the pass transistor is turned off, the internal circuits are shutdown, and the LDO is in a low-power mode.

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7 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

7.1 Application Information

7.1.1 Dropout Voltage

Dropout voltage (V_{DO}) is defined as the input voltage minus the output voltage $(V_{IN} - V_{OUT})$ when the pass transistor is fully on. This condition arises when the input voltage falls to the point where the error amplifier must drive the gate of the pass transistor to the rail and has no remaining headroom for the control loop to operate. The pass transistor is in the ohmic or triode region of operation, and acts as a switch. The dropout voltage directly specifies a minimum input voltage greater than the nominal programmed output voltage at which the output voltage is expected to stay in regulation. If the input voltage falls to less than the nominal output regulation, then the output voltage follows, minus the dropout voltage (V_{DO}) .

In dropout mode, the output voltage is no longer regulated, and transient performance is severely degraded. The device loses PSRR, and load transients can cause large output voltage deviation.

For a CMOS regulator, the dropout voltage is determined by the drain-source on-state resistance ($R_{DS(ON)}$) of the pass transistor. Therefore, if the linear regulator operates at less than the rated output current (I_{RATED} , see the *Recommended Operating Conditions* table), the dropout voltage for that current scales accordingly. The following equation calculates the $R_{DS(ON)}$ of the device.

$$R_{DS (ON)} = \frac{V_{DO}}{I_{RATED}}$$
 (4)

7.1.2 Reverse Current

The TPS7B4256-Q1 incorporates reverse current protection that prevents damage from a fault condition, resulting in V_{OUT} being higher than V_{IN} . During such a fault condition, where the V_{IN} and V_{OUT} absolute maximum ratings are not violated and $V_{OUT}-V_{IN}$ is less than 40 V, no damage occurs and less than 1.1 μ A of reverse current flows through the LDO. The reverse current comparator typically responds to a reverse voltage condition and, along with the body diode of the blocking PMOS transistor, limits the reverse current in 1 μ s.

7.2 Typical Application

Figure 7-1 shows a typical application circuit for the TPS7B4256-Q1.

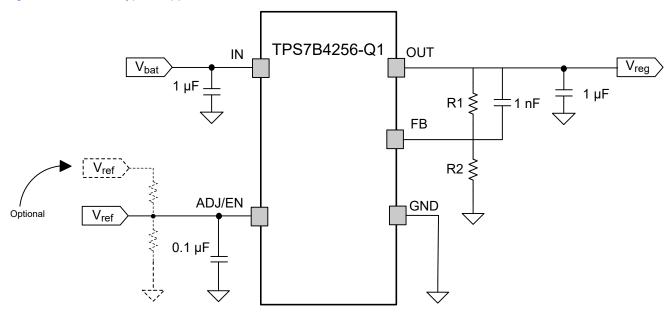


Figure 7-1. Typical Application Schematic

7.2.1 Design Requirements

Use the parameters listed in Table 7-1 for this design example.

Table 1-1. Design 1 drameters		
DESIGN PARAMETER EXAMPLE VALUES		
Input voltage	3 V to 40 V	
ADJ/EN reference voltage	2 V to 40 V	
Output voltage	2 V to 40 V	
Output current rating	70 mA	
Output capacitor range	1 μF to 100 μF	
Output capacitor ESR range	1 mΩ to 2 Ω	

Table 7-1. Design Parameters

7.2.2 Detailed Design Procedure

7.2.2.1 Input and Output Capacitor Selection

Depending on the end application, different values of external components can be used. An application can require a larger output capacitor during fast load steps to prevent a reset from occurring. Use a low ESR ceramic capacitor with a dielectric of type X5R or X7R for better load transient response.

The TPS7B4256-Q1 requires an output capacitor of at least 1 μ F (500 nF or larger capacitance) for stability and an equivalent series resistance (ESR) between 0.001 Ω and 2 Ω . Without the output capacitor, the regulator oscillates. For best transient performance, use X5R- and X7R-type ceramic capacitors because these capacitors have minimal variation in value and ESR over temperature. When choosing a capacitor for a specific application, be mindful of the DC bias characteristics for the capacitor. Higher output voltages cause a significant derating of the capacitor. For best performance, the maximum recommended output capacitor is 100 μ F.

An input capacitor is not required for stability, however, good analog practice is to connect a capacitor (500 nF or higher) between the GND and IN pin of the TPS7B4256-Q1. Some input supplies have a high impedance, thus placing the input capacitor on the input supply helps reduce input impedance. This capacitor counteracts reactive input sources and improves transient response, input ripple, and PSRR. If the input supply has a high

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impedance over a large range of frequencies, use several input capacitors in parallel to lower the impedance over frequency. Use a higher-value capacitor if large, fast rise-time load transients are anticipated, or if the device is located several inches from the input power source.

7.2.2.2 Feedback Resistor Selection

V_{OUT} is set by the voltage at the ADJ/EN pin and the external feedback resistors R₁ and R₂ according to the following equation:

$$V_{OUT} = V_{ADJ/EN} \times \left(1 + \frac{R_1}{R_2}\right) \tag{5}$$

To ignore the FB pin current error term in the V_{OUT} equation, set the feedback divider current to 100 times the FB pin current listed in the *Electrical Characteristics* table. This setting provides the maximum feedback divider series resistance, as shown in the following equation:

$$R_1 + R_2 \le \frac{V_{OUT}}{(I_{FB} \times 100)}$$
 (6)

7.2.2.3 Feedforward Capacitor

A feedforward capacitor (CFF) is recommended to be connected between the OUT pin and the FB pin. CFF improves transient, noise, and PSRR performance. A higher capacitance C_{FF} can be used; however, the start-up time increases. For a detailed description of C_{FF} tradeoffs, see the *Pros and Cons of Using a Feedforward* Capacitor with a Low-Dropout Regulator application note.

As shown in Figure 7-2, poor layout practices and using long traces at the FB pin results in the formation of a parasitic capacitor (C_{FB}).

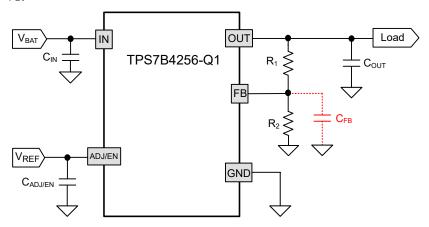


Figure 7-2. Formation of Parasitic Capacitor at the FB Pin

CFB, along with the feedback resistors R1 and R2 can result in the formation of an uncompensated pole in the transfer function of the loop gain. A CFB value as small as 7 pF can cause the parasitic pole frequency, given by Equation 7, to fall within the bandwidth of the LDO and result in instability.

$$f_{P} = \frac{1}{(2 \times \pi \times C_{FR} \times (R_1 \parallel R_2))} \tag{7}$$

Adding a feedforward capacitor (C_{FF}), as shown in Figure 7-3, creates a zero in the loop gain transfer function that can compensate for the parasitic pole created by C_{FB} . Equation 8 and Equation 9 calculate the pole and zero frequencies.

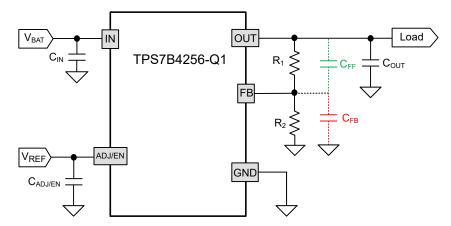


Figure 7-3. Feedforward Capacitor Can Compensate the Effects of the Parasitic Capacitor

$$f_{P} = \frac{1}{(2 \times \pi \times (R_{1} \parallel R_{2}) \times (C_{FF} + C_{FB}))}$$
(8)

$$f_Z = \frac{1}{(2 \times \pi \times C_{FF} \times R_1)} \tag{9}$$

The C_{FF} value that makes f_P equal to f_Z , and result in a pole-zero cancellation, depends on the values of C_{FB} and the feedback resistors used in the application. Alternatively, if the feedforward capacitor is selected so that $C_{FF} \gg C_{FB}$, then the pole and zero frequencies given by Equation 8 and Equation 9 are related as:

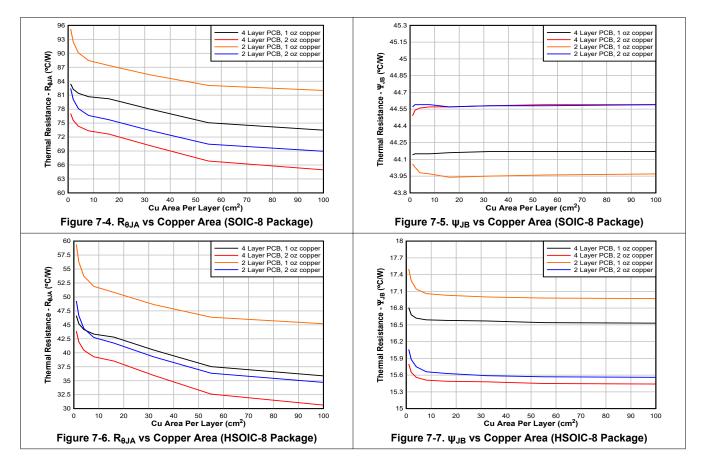
$$\frac{f_{p}}{f_{z}} \approx \left(1 + \frac{R_{1}}{R_{2}}\right) = \frac{V_{OUT}}{V_{ADJ/EN}}$$
(10)

In most applications, particularly where a 3.3-V or 5-V V_{OUT} is generated, this ratio is not very large, implying that the frequencies are located close to each other and therefore the parasitic pole is compensated. Even for large V_{OUT} values, where this ratio can be as large as 20, a C_{FF} value in the range 100 pF $\leq C_{FF} \leq$ 10 nF typically helps prevent instability caused by the parasitic capacitance on the feedback node.

Following good layout practices, as described in the *Layout Guidelines* section and in the *TRKRLDOEVM-119 General-Purpose Tracker LDO Evaluation Module* user guide, helps minimize the parasitic feedback pin capacitance to values that prevent the resulting parasitic pole from causing instability.

7.2.3 Application Curves

The following images illustrate the functions of $R_{\theta JA}$ and ψ_{JB} versus copper area and thickness for the SOIC-8 (D) and HSOIC-8 (DDA) packages. These plots are generated with a 101.6-mm × 101.6-mm × 1.6-mm PCB of two and four layers. For the 2-layer board, the bottom layer is a ground plane of constant size, and the top layer copper is connected to GND and varied. For the 4-layer board, the second layer is a ground plane of constant size, the third layer is a power plane of constant size, and the top and bottom layers copper fills are connected to GND and varied at the same rate. For the 4-layer board, inner planes use 1-oz copper thickness. Outer layers are simulated with both 1-oz and 2-oz copper thickness. A 3 × 3 array of thermal vias with a 300-µm drill diameter and 25-µm copper plating is located underneath the device. The thermal vias connect the top layer, the bottom layer and, in the case of the 4-layer board, the first inner GND plane. PowerPAD™ Thermally Enhanced Package application note discusses the impact that thermal vias have on thermal performance.



7.3 Power Supply Recommendations

The device is designed to operate from an input voltage supply range from 3 V to 40 V.

7.4 Layout

7.4.1 Layout Guidelines

For best overall performance, place all circuit components on the same side of the circuit board and as near as practical to the respective LDO pin connections. Place ground return connections to the input and output capacitor, and to the LDO ground pin as close as possible to each other, connected by a wide, component-side, copper surface. Using vias and long traces to the input and output capacitors is strongly discouraged and negatively affects system performance. Use a ground reference plane either embedded in the PCB or located on the bottom side of the PCB opposite the components. This reference plane serves to provide accuracy of the output voltage, shield noise, and behaves similarly to a thermal plane to spread (or sink) heat from the LDO device when connected to the thermal pad. In most applications, this ground plane is necessary to meet thermal requirements.

7.4.1.1 Package Mounting

Solder-pad footprint recommendations for the TPS7B4256-Q1 are available at the end of this document and at www.ti.com.

7.4.1.2 Board Layout Recommendations to Improve PSRR and Noise Performance

To improve AC performance (such as PSRR, output noise, and transient response), design the board with separate ground planes for V_{IN} and V_{OUT} , with each ground plane connected only at the GND pin of the device. In addition, the ground connection for the output capacitor must connect directly to the GND pin of the device.

Equivalent series inductance (ESL) and ESR must be minimized in order to maximize performance and provide stability. Every capacitor must be placed as close as possible to the device and on the same side of the printed circuit board (PCB) as the regulator.

Do not place any of the capacitors on the opposite side of the PCB from where the regulator is installed. The use of vias and long traces is strongly discouraged because of the negative impact on system performance. Vias and long traces can also cause instability.

If possible, and to provide the maximum performance denoted in this product data sheet, use the same layout pattern used for the TPS7B4256-Q1 evaluation board, available at www.ti.com.

7.4.1.3 Power Dissipation and Thermal Considerations

Equation 11 calculates the device power dissipation.

$$P_D = I_{OUT} \times (V_{IN} - V_{OUT}) + I_O \times V_{IN}$$
(11)

where:

- P_D = Continuous power dissipation
- I_{OUT} = Output current
- V_{IN} = Input voltage
- V_{OUT} = Output voltage
- I_O = Quiescent current

Because I_Q is much less than I_{QUT} , the term $I_Q \times V_{IN}$ in Equation 11 can be ignored.

Calculate the junction temperature (T_J) with Equation 12 for a device under operation at a given ambient air temperature (T_A) .

$$T_{J} = T_{A} + (R_{\theta,JA} \times P_{D}) \tag{12}$$

where:

• $R_{\theta JA}$ = Junction-to-junction-ambient air thermal impedance

Equation 13 calculates a rise in junction temperature because of power dissipation.

$$\Delta T = T_J - T_A = (R_{\theta,JA} \times P_D) \tag{13}$$

The maximum ambient air temperature (T_{AMAX}) at which the device can operate can be calculated with Equation 14 for a given maximum junction temperature (T_{JMAX}).

$$T_{AMAX} = T_{JMAX} - (R_{\theta JA} \times P_D) \tag{14}$$

7.4.1.4 Thermal Performance Versus Copper Area

The most used thermal resistance parameter $R_{\theta JA}$ is highly dependent on the heat-spreading capability built into the particular PCB design, and therefore varies according to the total copper area, copper weight, and location of the planes. The $R_{\theta JA}$ recorded in the *Thermal Information* table is determined by the JEDEC standard (Figure 7-8), PCB, and copper-spreading area, and is only used as a relative measure of package thermal performance.



For a well-designed thermal layout, $R_{\theta JA}$ is actually the sum of the package junction-to-case (bottom) thermal resistance ($R_{\theta JCbot}$) plus the thermal resistance contribution by the PCB copper.

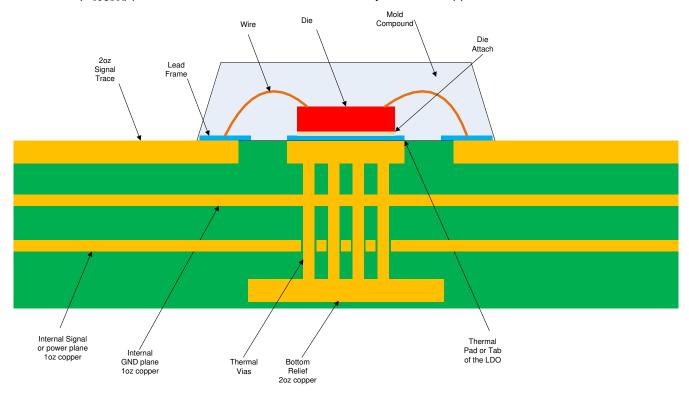
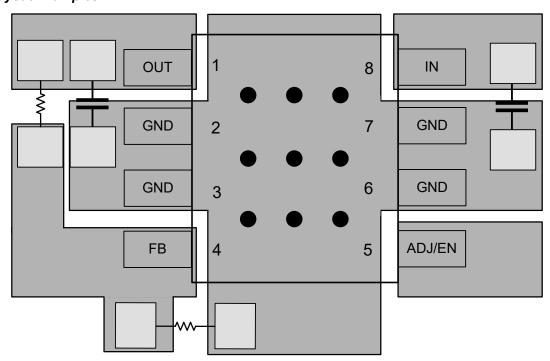


Figure 7-8. JEDEC Standard 2s2p PCB

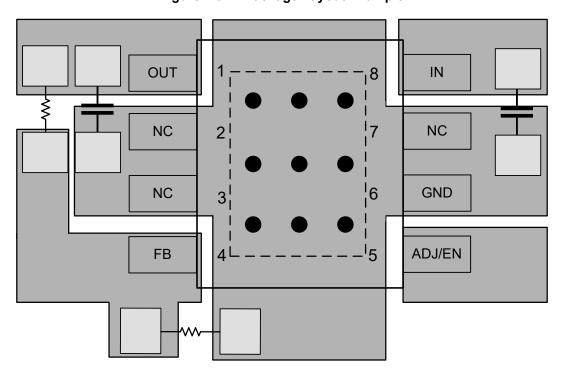


7.4.1.5 Layout Examples



Circles denote PCB via connections

Figure 7-9. D Package Layout Example



Circles denote PCB via connections

Figure 7-10. DDA Package Layout Example



8 Device and Documentation Support

8.1 Device Support

8.1.1 Device Nomenclature

Table 8-1. Device Nomenclature(1)

PRODUCT	V _{OUT}
TPS7B4256 Q DDAR Q1	In the HSOIC (DDA) package: Q indicates that this device is a grade-1 device in accordance with the AEC-Q100 standard. R is the packaging quantity. Q1 indicates that this device is an automotive grade (AEC-Q100) device.
TPS7B4256 Q DR Q1	In the SOIC (D) package: Q indicates that this device is a grade-1 device in accordance with the AEC-Q100 standard. R is the packaging quantity. Q1 indicates that this device is an automotive grade (AEC-Q100) device.

⁽¹⁾ For the most current package and ordering information see the Package Option Addendum at the end of this document, or visit the device product folder on www.ti.com.

8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on Notifications to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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8.4 Trademarks

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8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision * (September 2023) to Revision A (November 2023)



10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status (1)	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
TPS7B4256QDDARQ1	Active	Production	SO PowerPAD (DDA) 8	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	B4256F
TPS7B4256QDDARQ1.A	Active	Production	SO PowerPAD (DDA) 8	2500 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	B4256F
TPS7B4256QDRQ1	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	B4256E
TPS7B4256QDRQ1.A	Active	Production	SOIC (D) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	B4256E

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

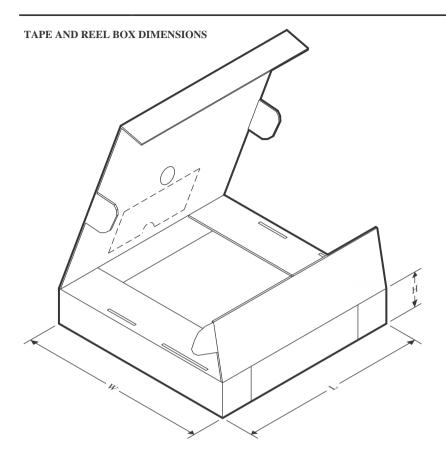


*All dimensions are nominal

	Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
	TPS7B4256QDDARQ1	SO PowerPAD	DDA	8	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
j	TPS7B4256QDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1



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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TPS7B4256QDDARQ1	SO PowerPAD	DDA	8	2500	353.0	353.0	32.0	
TPS7B4256QDRQ1	SOIC	D	8	2500	340.5	338.1	20.6	



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4202561/G





PLASTIC SMALL OUTLINE



NOTES:

PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MS-012.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 (www.ti.com/lit/slma002) and SLMA004 (www.ti.com/lit/slma004).
- 9. Size of metal pad may vary due to creepage requirement.
- 10. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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